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ELF-Induced DNA Breaks

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Many research papers in the literature have reported DNA damages (particularly DNA strand breaks) in different types of biologically cells after exposure to ELF EMF. Various other reports have also indicated that ELF EMF affects DNA repair in cells. It seems that intensity and duration of exposure interact. High intensity/short exposure could produce similar genotoxic effect as low intensity/long duration exposure. Free radical formation in cells mediates some of these effects of ELF EMF. DNA damages are cumulative and could lead to functional cellular changes, cancer, cell death, and serious health effects.